

International **TOR** Rectifier

POWER MOSFET SURFACE MOUNT(SMD-1)

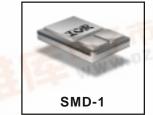
Product Summary

Part Number	RDS(on)	ID
IRFN150	0.07 Ω	34A

HEXFET® MOSFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance. HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.

PD - 91547C

IRFN150 JANTX2N7224U JANTXV2N7224U REF:MIL-PRF-19500/592 100V, N-CHANNEL HEXFET[®] MOSFETTECHNOLOGY



Features:

- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed
- Electrically Isolated
- Surface Mount
- Dynamic dv/dt Rating
- Light-weight

and the first the	Parameter		Units	
ID @ VGS = 10V, TC = 25°C Continuous Drain Current		34		
ID @ VGS = 10V, TC = 100°C Continuous Drain Current		21	A	
IDM	Pulsed Drain Current ①	136	-18	
PD @ TC = 25°C	Max. Power Dissipation	150	W	
	Linear Derating Factor	1.2	W/°C	
VGS Gate-to-Source Voltage		±20	V	
EAS	Single Pulse Avalanche Energy 2	150	mJ	
IAR Avalanche Current 1		34	Α	
EAR	Repetitive Avalanche Energy 1	15	mJ	
dv/dt	Peak Diode Recovery dv/dt 3	5.5	V/ns	
Tj	Operating Junction	-55 to 150		
TSTG	Storage Temperature Range		°C	
	Package Mounting Surface Temperature	300(for 5 seconds)		
1 5 10 10	Weight	2.6 (Typical)	g	

Absolute Maximum Ratings

For footnotes refer to the last page



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	Parameter	Min	Тур	Max	Units	Test Conditions
BVDSS	Drain-to-Source Breakdown Voltage	100	—	—	V	VGS = 0V, ID = 1.0mA
$\Delta BV_{DSS}/\Delta T_{J}$	Temperature Coefficient of Breakdown Voltage	—	0.13	—	V/°C	Reference to 25°C, $I_D = 1.0$ mA
RDS(on)	Static Drain-to-Source On-State	—	—	0.07	Ω	VGS = 10V, ID = 21A
. ,	Resistance	—	—	0.081	52	VGS = 10V, ID = 34A
VGS(th)	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$
9fs	Forward Transconductance	9.0	—	—	S(7)	V _{DS} > 15V, I _{DS} = 21A ④
IDSS	Zero Gate Voltage Drain Current	—	—	25	μA	VDS= 80V ,VGS=0V
		—	—	250	μΑ	VDS = 80V,
						$V_{GS} = 0V, T_{J} = 125^{\circ}C$
IGSS	Gate-to-Source Leakage Forward	_	—	100	0	VGS = 20V
IGSS	Gate-to-Source Leakage Reverse	—	—	-100	nA	VGS = -20V
Qg	Total Gate Charge	—	—	125		VGS =10V, ID = 34A
Qgs	Gate-to-Source Charge	—	—	22	nC	$V_{DS} = 50V$
Qgd	Gate-to-Drain ('Miller') Charge	—	—	65		
td(on)	Turn-On Delay Time	—	—	35		$V_{DD} = 50V, I_D = 34A,$
tr	Rise Time	—	—	190	ns	VGS =10V, RG = 2.35Ω
^t d(off)	Turn-Off Delay Time	—	—	170	115	
tf	Fall Time	—	—	130		
LS+LD	Total Inductance	_	4.0	—	nH	Measured from the center of drain
						pad to center of source pad.
C _{iss}	Input Capacitance		3700			$V_{GS} = 0V, V_{DS} = 25V$
Coss	Output Capacitance		1100		pF	f = 1.0MHz
Crss	Reverse Transfer Capacitance	—	200	—		

Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

Source-Drain Diode Ratings and Characteristics

	Parameter	Min	Тур	Max	Units	Test Conditions
IS	Continuous Source Current (Body Diode)	—		34	۸	
ISM	Pulse Source Current (Body Diode) ①	—	—	136	A	
VSD	Diode Forward Voltage	—	—	1.8	V	Tj = 25°C, IS = 34A, VGS = 0V ④
t _{rr}	Reverse Recovery Time	—	—	500	nS	Tj = 25°C, IF = 34A, di/dt ≤ 100A/μs
QRR	Reverse Recovery Charge	—	—	2.9	μC	$V_{DD} \leq 30V $ (4)
ton	Forward Turn-On Time Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by LS + LD.					

Thermal Resistance

	Parameter	Min	Тур	Max	Units	Test Conditions
R _{th} JC	Junction-to-Case	—	—	0.83	°C/W	
RthJ-PCB	Junction-to-PC board	—	3.0	—	C/ VV	Soldered to a copper-clad PC board

Note: Corresponding Spice and Saber models are available on the G&S Website.

For footnotes refer to the last page

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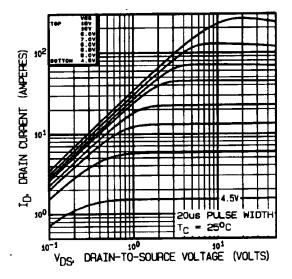
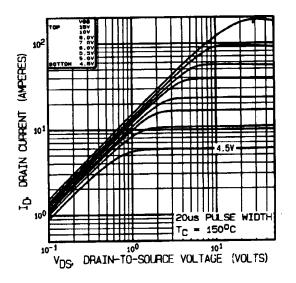
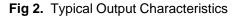


Fig 1. Typical Output Characteristics





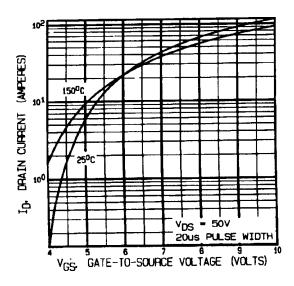
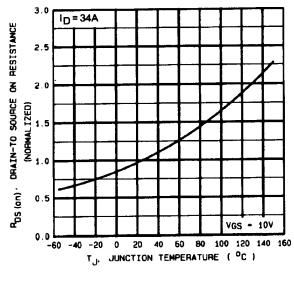
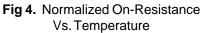


Fig 3. Typical Transfer Characteristics





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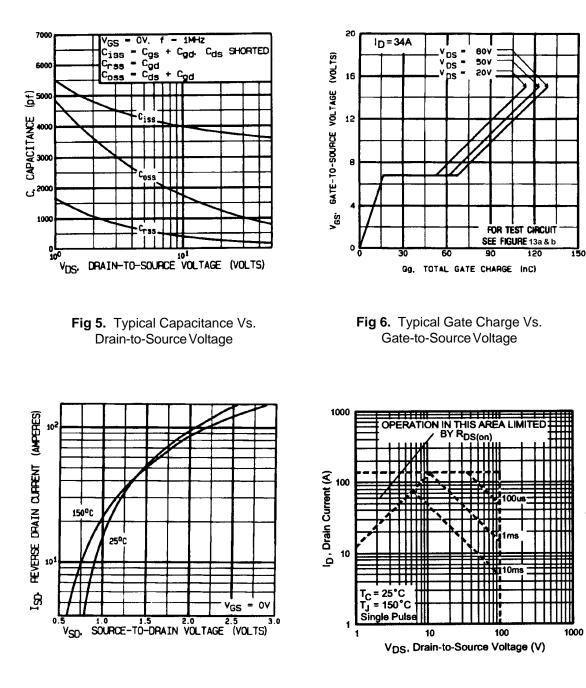
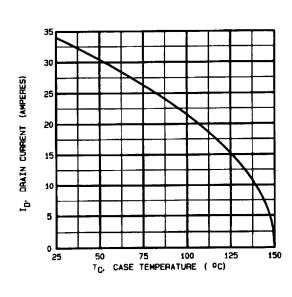


Fig 7. Typical Source-Drain Diode Forward Voltage

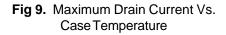
Fig 8. Maximum Safe Operating Area

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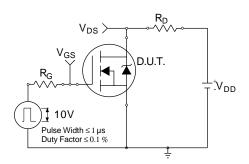


Fig 10a. Switching Time Test Circuit

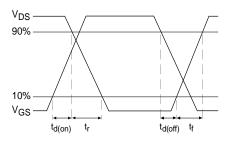


Fig 10b. Switching Time Waveforms

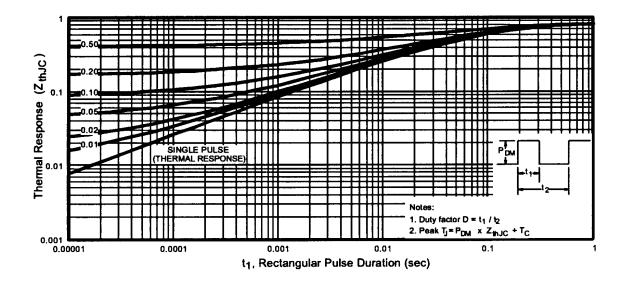


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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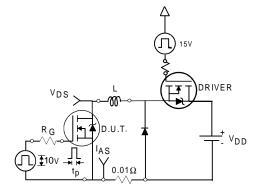


Fig 12a. Unclamped Inductive Test Circuit

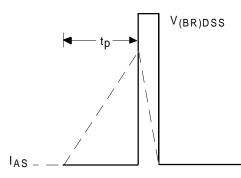
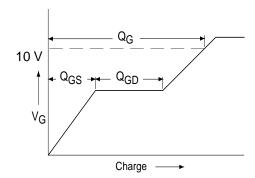
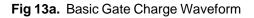
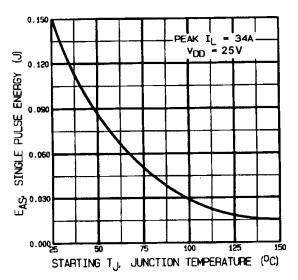
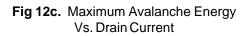


Fig 12b. Unclamped Inductive Waveforms









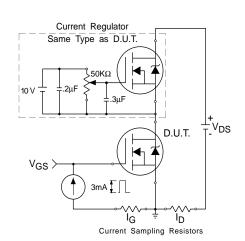


Fig 13b. Gate Charge Test Circuit

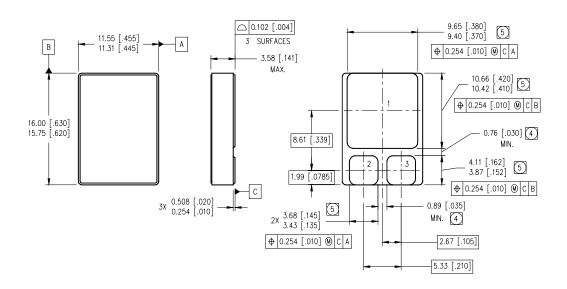
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Footnotes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- \textcircled{V}_{DD} = 25V, starting TJ = 25°C, L= 0.26mH Peak IL = 34A, VGS = 10V
- $\label{eq:ISD} \begin{array}{ll} & I_{SD} \leq 34 \text{A}, \mbox{ di/dt} \leq 200 \text{A}/\mu \text{s}, \\ & V_{DD} \leq 100 \text{V}, \mbox{ T}_J \leq 150^\circ \text{C} \end{array}$
- ④ Pulse width \leq 300 µs; Duty Cycle \leq 2%

IRFN150

Case Outline and Dimensions — SMD-1



NOTES:

- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. CONTROLLING DIMENSION: INCH.
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4 DIMENSION INCLUDES METALLIZATION FLASH.
- 5 DIMENSION DOES NOT INCLUDE METALLIZATION FLASH.

PAD ASSIGNMENTS 1- DRAIN 2- GATE 3- SOURCE

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Data and specifications subject to change without notice. 01/02